


<b>Search Notes</b> 	<b>Application/Control No.</b> 10671548	<b>Applicant(s)/Patent Under Reexamination</b> MURAKAWA, AKIRA
	<b>Examiner</b> Gee, Jason	<b>Art Unit</b> 2434

SEARCHED			
Class	Subclass	Date	Examiner
713	156, 173	11/10/2009	JKG

SEARCH NOTES		
Search Notes	Date	Examiner
EAST - USPGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	11/10/2009	JKG
PALM - Inventor Name Search	11/10/2009	JKG
Google Scholar - Root Certificates	11/10/2009	JKG

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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